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October 2014

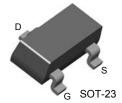
2N7002L N-Channel Enhancement Mode Field Effect Transistor

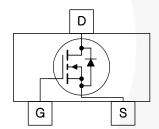
Features

- High Density Cell Design for Low R_{DS(ON)}
- · Voltage Controlled Small Signal Switch
- Rugged and Reliable
- · High Saturation Current Capability
- · Very Low Capacitance
- · Fast Switching Speed

Description

This N-channel enhancement mode field effect transistor is produced using high cell density, trench MOSFET technology. This product minimizes on-state resistance while providing rugged, reliable and fast switching performance. This product is particularly suited for low-voltage, low-current applications such as small servo motor control, power MOSFET gate drivers, logic level translator, high speed line drivers, power management/power supply, and switching applications.





Ordering Information

Part Number Marking		Package	Packing Method	
2N7002L	70L	SOT-23 3L	Tape and Reel	

© 2014 Fairchild Semiconductor Corporation 2N7002L Rev. 1.0.1

1

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only. Values are at $T_A = 25^{\circ}\text{C}$ unless otherwise noted.

Symbol	Parameter		Value	Unit	
V _{DSS}	Drain-Source Voltage		60	V	
V_{DGR}	Drain-Gate Voltage ($R_{GS} \le 1 M\Omega$)		60	V	
V	Gate-Source Voltage	Continuous	±20	V	
V_{GSS}		Non Repetitive ($t_p < 50 \mu s$)	±40		
I _D	Maximum Drain Current	Continuous	115	mA	
	Maximum Drain Current	Pulsed	800		
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering Purposes, 1/16 inch from Case for 10 Seconds		300	°C	

Thermal Characteristics(1)

Values are at $T_A = 25$ °C unless otherwise noted.

Symbol	Parameter	Value	Unit
P _D	Maximum Power Dissipation	200	mW
	Derate Above 25°C	1.6	mW/°C
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	380	°C/W

Note:

1. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 380°C/W when mounted on a minimum pad.

Scale 1: 1 on letter size paper

ESD Rating(2)

Symbol	Parameter	Value	Unit
HBM	Human Body Model per ANSI/ESDA/JEDEC JS-001-2012		V
CDM	Charged Device Model per JEDEC C101C	>2000	V

Note:

2. ESD values are in typical, no over-voltage rating is implied, ESD CDM zap voltage is 2000 V maximum.

Electrical Characteristics

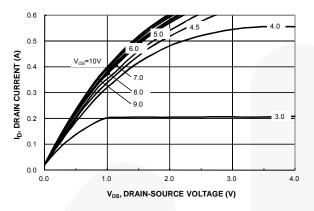
Values are at $T_A = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Charact	eristics			1	I.	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 10 \mu\text{A}$	60.0	65.2		V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V		0.024	1	μΑ
		V _{DS} = 60 V, V _{GS} = 0 V, T _J = 125°C		0.080	500	
I _{GSSF}	Gate-Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V		0.107	100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	V _{GS} = -20 V, V _{DS} = 0 V		-0.037	-100	nA
On Charact	eristics ⁽³⁾			1	I.	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	0.80	1.81	2.50	V
` ,		V _{GS} = 10 V, I _D = 500 mA		3.35	7.50	Ω
		V _{GS} = 10 V, I _D = 500 mA, T _J = 100°C		5.62	13.50	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 5 \text{ V}, I_D = 50 \text{ mA}$		2.68	7.50	
		V _{GS} = 5 V, I _D = 50 mA, T _J = 100°C		3.97	13.50	
	. / .	V _{GS} = 10 V, I _D = 500 mA		1.68	3.75	V
$V_{DS(ON)}$	Drain-Source On-Voltage	V _{GS} = 5 V, I _D = 50 mA		0.13	1.50	
	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} \ge 2 V_{DS(ON)}$	500	557		mA
$I_{D(ON)}$		V _{GS} = 4.5 V, V _{DS} = 10 V	75	571		
9 _{FS}	Forward Trans-conductance	$V_{DS} \ge 2 V_{DS(ON)}$, $I_D = 200 \text{ mA}$	80	214		mS
Dynamic Cl	haracteristics				I.	
C _{iss}	Input Capacitance			12.8	50	pF
C _{oss}	Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		3.25	25	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1.0 WILL		1.52	5	pF
R_{G}	Gate Resistance	V _{GS} = 0 V, f = 1.0 MHz		22.2		Ω
Switching (Characteristics ⁽³⁾			1	I.	7
t _{on}	Turn-On Time	V_{DD} = 30 V, R_{L} = 150 Ω , I_{D} = 200 mA, V_{GS} = 10 V, R_{GEN} = 25 Ω		4.35	20	ns
t _{off}	Turn-Off Time			15.6	20	ns
Drain-Sour	ce Diode Characteristics and Maxin	num Ratings				
I _S	Maximum Continuous Drain-Source Diode Forward Current				115	mA
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				0.8	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V, } I_S = 115 \text{ mA}^{(3)}$		0.818	1.5	V

Note:

3. Pulse test: pulse width \leq 300 μ s, duty cycle \leq 2.0%.

Typical Performance Characteristics



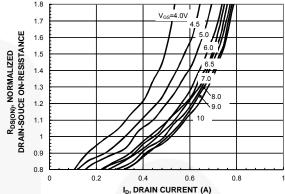
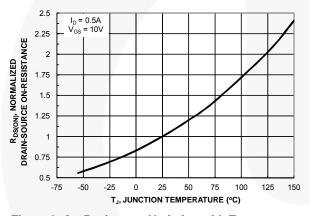


Figure 1. On-Region Characteristics

Figure 2. On-Resistance Variation with Gate Voltage and Drain Current



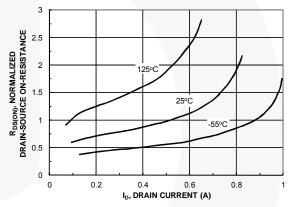
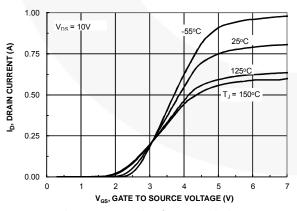


Figure 3. On-Resistance Variation with Temperature

Figure 4. On-Resistance Variation with Drain Current and Temperature



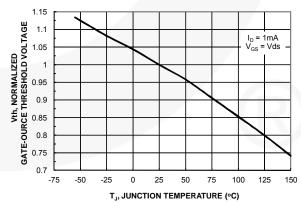


Figure 5. Transfer Characteristics

Figure 6. Gate Threshold Variation with Temperature

Typical Performance Characteristics (Continued)

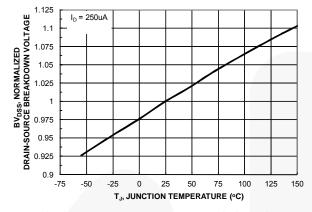
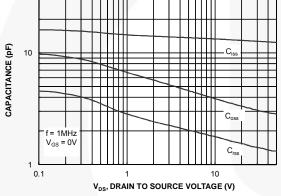


Figure 7. Breakdown Voltage Variation with Temperature

Figure 8. Body Diode Forward Voltage Variation with Source Current and Temperature



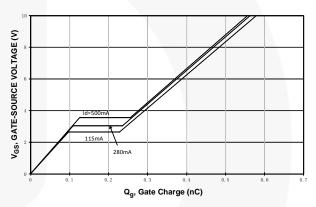
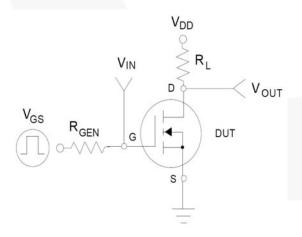


Figure 9. Capacitance Characteristics

Figure 10. Gate Charge Characteristics



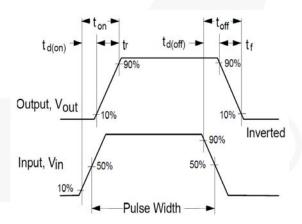


Figure 11.

Figure 12. Switching Waveforms

Typical Performance Characteristics (Continued)

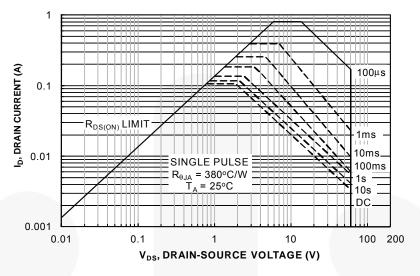


Figure 13. Maximum Safe Operating Area

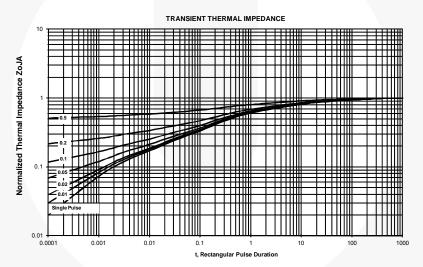
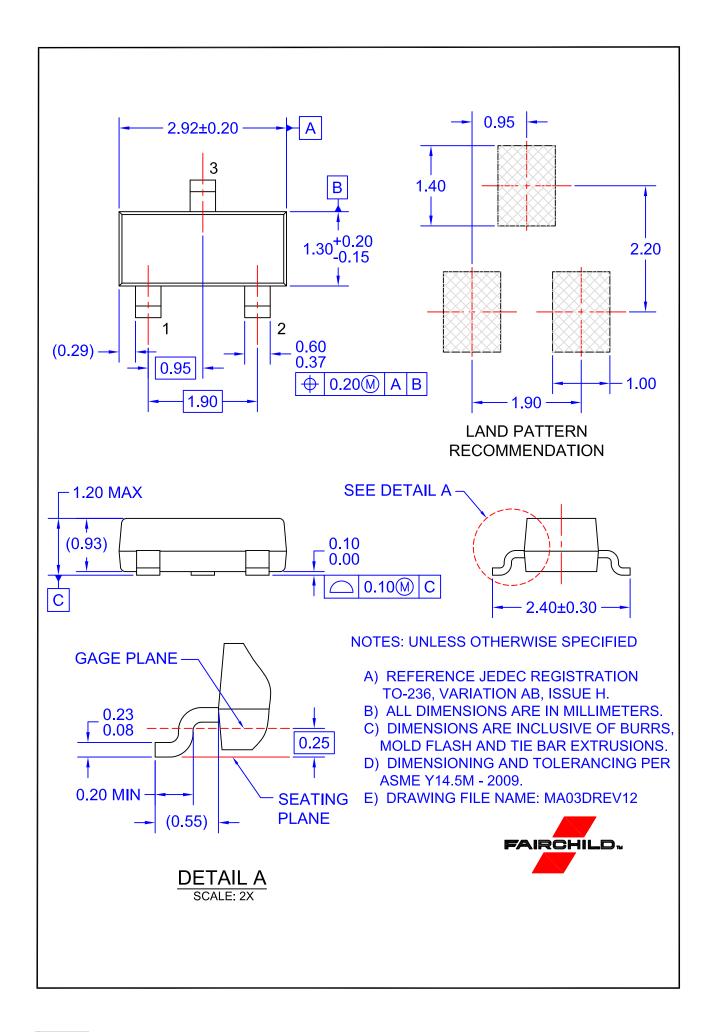


Figure 14. Transient Thermal Response Curve



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